Cedric J Powell

List of Publications by Year in Descending Order

162 papers	12,632 citations	47 h-index	111 g-index
169 ext. papers	13,413 ext. citations	2.8 avg, IF	6.46 L-index

#	Paper	IF	Citations
162	elsepaDirac partial-wave calculation of elastic scattering of electrons and positrons by atoms, positive ions and molecules (New Version Announcement). *Computer Physics Communications*, **2021**, 261, 107704	4.2	3
161	Applications of the National Institute of Standards and Technology (NIST) database for the simulation of electron spectra for surface analysis for quantitative x-ray photoelectron spectroscopy of nanostructures. *Journal of Vacuum Science and Technology A: Vacuum, Surfaces and Films*, **2021**, 39, 063205	2.9	0
160	Practical guide for inelastic mean free paths, effective attenuation lengths, mean escape depths, and information depths in x-ray photoelectron spectroscopy. *Journal of Vacuum Science and Technology A: Vacuum, Surfaces and Films*, **2020**, 38, 023209	2.9	42
159	Proliferation of Faulty Materials Data Analysis in the Literature. *Microscopy and Microanalysis*, **2020**, 26, 1-2	0.5	32
158	Effective Attenuation Lengths for Different Quantitative Applications of X-ray Photoelectron Spectroscopy. *Journal of Physical and Chemical Reference Data*, **2020**, 49, 033102	4.3	14
157	Effective attenuation length dependence on photoelectron kinetic energy for gold from 1 keV to 10 keV: Role of island growth in overlayer experiments. *Journal of Electron Spectroscopy and Related Phenomena*, **2019**, 236, 27-32	1.7	5
156	Practical Guides for X-Ray Photoelectron Spectroscopy (XPS): First Steps in planning, conducting and reporting XPS measurements. *Journal of Vacuum Science and Technology A: Vacuum, Surfaces and Films*, **2019**, 37,	2.9	80
155	Electron inelastic mean free paths in compounds. *Journal of Surface Analysis (Online)*, **2019**, 26, 106-107	0.1	1
154	Comparisons of Analytical Approaches for Determining Shell Thicknesses of Core-Shell Nanoparticles by X-ray Photoelectron Spectroscopy. *Journal of Physical Chemistry C*, **2018**, 122, 4073-4082	3.8	18
153	Calculations of electron inelastic mean free paths. XII. Data for 42 inorganic compounds over the 50 eV to 200 keV range with the full Penn algorithm. *Surface and Interface Analysis*, **2018**, 51, 427-457	1.5	43
152	Simulated photoelectron intensities at the aqueous solution-air interface for flat and cylindrical (microjet) geometries. *Physical Chemistry Chemical Physics*, **2017**, 19, 6330-6333	3.6	5
151	Effective attenuation lengths for quantitative determination of surface composition by Auger-electron spectroscopy and X-ray photoelectron spectroscopy. *Journal of Electron Spectroscopy and Related Phenomena*, **2017**, 281, 1-2	1.7	12
150	Quantitative analysis of trace levels of surface contamination by X-ray photoelectron spectroscopy. Part II: Systematic uncertainties and absolute quantification. *Surface and Interface Analysis*, **2017**, 49, 1214-1224	1.5	9
149	Quantitative analysis of trace levels of surface contamination by X-ray photoelectron spectroscopy Part I: statistical uncertainty near the detection limit. *Surface and Interface Analysis*, **2017**, 49, 1187-1205	1.5	7
148	Calculations of Electron Inelastic Mean Free Paths. XI. Data for Liquid Water for Energies from 50 eV to 30 keV. *Surface and Interface Analysis*, **2017**, 49, 238-252	1.5	56
147	Inelastic Mean Free Paths, Mean Escape Depths, Information Depths, and Effective Attenuation Lengths for Hard X-ray Photoelectron Spectroscopy. *Springer Series in Surface Sciences*, **2016**, 111-140	0.4	7
146	Quantitative interpretation of molecular dynamics simulations for X-ray photoelectron spectroscopy of aqueous solutions. *Journal of Chemical Physics*, **2016**, 144, 154704	3.9	29

145	Use of the Bethe Equation for Inner-Shell Ionization by Electron Impact. *Journal of Applied Physics*, **2016**, 119,	2.5	7
144	Growth of Surface Analysis and the Development of Databases and Modeling Software for Auger-Electron Spectroscopy and X-ray Photoelectron Spectroscopy. *Microscopy Today*, **2016**, 24, 16-23	0.4	14
143	Evaluation of Two Methods for Determining Shell Thicknesses of Core-Shell Nanoparticles by X-ray Photoelectron Spectroscopy. *Journal of Physical Chemistry C*, **2016**, 120, 22730-22738	3.8	16
142	Evaluating the Internal Structure of Core-Shell Nanoparticles Using X-ray Photoelectron Intensities and Simulated Spectra. *Journal of Physical Chemistry C*, **2015**, 119, 17687-17696	3.8	36
141	Development of standards for reliable surface analyses by ISO technical committee 201 on surface chemical analysis. *Surface and Interface Analysis*, **2015**, 47, 127-134	1.5	7
140	Sample-morphology effects on x-ray photoelectron peak intensities. III. Simulated spectra of model core-shell nanoparticles. *Journal of Vacuum Science and Technology A: Vacuum, Surfaces and Films*, **2015**, 33, 05E113	2.9	4
139	Calculations of electron inelastic mean free paths. X. Data for 41 elemental solids over the 50 eV to 200 keV range with the relativistic full Penn algorithm. *Surface and Interface Analysis*, **2015**, 47, 871-888	1.5	183
138	Cross Sections for Inner-Shell Ionization by Electron Impact. *Journal of Physical and Chemical Reference Data*, **2014**, 43, 013102	4.3	98
137	Interlaboratory study comparing analyses of simulated angle-resolved X-ray photoelectron spectroscopy data. *Surface and Interface Analysis*, **2014**, 46, 321-332	1.5	1
136	Sample-morphology effects on x-ray photoelectron peak intensities. II. Estimation of detection limits for thin-film materials. *Journal of Vacuum Science and Technology A: Vacuum, Surfaces and Films*, **2014**, 32, 050603	2.9	9
135	Interpretation of nanoparticle X-ray photoelectron intensities. *Applied Physics Letters*, **2014**, 104, 243106	3.4	28
134	New Data Resources and Applications for AES and XPS. *Journal of Surface Analysis (Online)*, **2014**, 20, 155-160	0.1	8
133	Simulation of Electron Spectra for Surface Analysis (SESSA)for quantitative interpretation of (hard) X-ray photoelectron spectra(HAXPES). *Journal of Electron Spectroscopy and Related Phenomena*, **2013**, 190, 137-143	1.7	22
132	Effective attenuation lengths for photoelectrons in thin films of silicon oxynitride and hafnium oxynitride on silicon. *Surface and Interface Analysis*, **2013**, 45, 628-638	1.5	12
131	Sample-morphology effects on x-ray photoelectron peak intensities. *Journal of Vacuum Science and Technology A: Vacuum, Surfaces and Films*, **2013**, 31, 021402	2.9	15
130	Electron Based Methods: 3.2.3 Spectroscopic Databases and Standardization for Auger-Electron Spectroscopy and X-Ray Photoelectron Spectroscopy **2013**, 215-252		1
129	Calculations of electron inelastic mean free paths. IX. Data for 41 elemental solids over the 50 eV to 30 keV range. *Surface and Interface Analysis*, **2011**, 43, 689-713	1.5	647
128	Photoelectron angular distributions of Cu, Ag, Pt and Au samples: experiments and simulations. *Surface and Interface Analysis*, **2011**, 43, 934-939	1.5	4

127	Effects of elastic scattering and analyzer-acceptance angle on the analysis of angle-resolved X-ray photoelectron spectroscopy data. *Surface and Interface Analysis*, **2011**, 43, 1046-1056	1.5	11
126	Recommended Auger-electron kinetic energies for 42 elemental solids. *Journal of Electron Spectroscopy and Related Phenomena*, **2010**, 182, 11-18	1.7	14
125	Simulation of parallel angle-resolved X-ray photoelectron spectroscopy data. *Surface and Interface Analysis*, **2010**, 42, 1072-1075	1.5	6
124	Evaluation of uncertainties in X-ray photoelectron spectroscopy intensities associated with different methods and procedures for background subtraction. I. Spectra for monochromatic Al X-ray. *Surface and Interface Analysis*, **2009**, 41, 269-294	1.5	15
123	Evaluation of uncertainties in X-ray photoelectron spectroscopy intensities associated with different methods and procedures for background subtraction. II. Spectra for unmonochromated Al and Mg X-rays. *Surface and Interface Analysis*, **2009**, 41, 804-813	1.5	4
122	Cross sections for ionization of K, L and M shells of atoms by impact of electrons and positrons with energies up to 1 GeV: Analytical formulas. *Atomic Data and Nuclear Data Tables*, **2009**, 95, 871-909	2	82
121	Practical expressions for the mean escape depth, the information depth, and the effective attenuation length in Auger-electron spectroscopy and x-ray photoelectron spectroscopy. *Journal of Vacuum Science and Technology A: Vacuum, Surfaces and Films*, **2009**, 27, 253-261	2.9	84
120	Practical formulas for inner-shell ionization cross sections by electron impact: Applications in quantitative Auger electron spectroscopy. *Journal of Applied Physics*, **2009**, 106, 053706	2.5	4
119	Modified predictive formula for the electron stopping power. *Journal of Applied Physics*, **2008**, 103, 063708	2.5	21
118	Calculations of stopping powers of 100eV–30keV electrons in 31 elemental solids. *Journal of Applied Physics*, **2008**, 103, 063707	2.5	35
117	Summary of ISO/TC 201 Standard: XXIX. ISO 20903: 2006—Surface chemical analysis—Auger electron spectroscopy and X-ray photoelectron spectroscopy—Methods used to determine peak intensities and information required when reporting results. *Surface and Interface Analysis*, **2007**, 39, 464-466	1.5	8
116	Improved algorithm for calculating transport cross sections of electrons with energies from 50eVto30keV. *Physical Review B*, **2007**, 76,	3.3	30
115	Refined calculations of effective attenuation lengths for SiO2 film thicknesses by x-ray photoelectron spectroscopy. *Applied Physics Letters*, **2006**, 89, 252116	3.4	14
114	Suppression of orange-peel coupling in magnetic tunnel junctions by preoxidation. *Applied Physics Letters*, **2006**, 88, 162508	3.4	19
113	Distinguishability of N composition profiles in SiON films on Si by angle-resolved x-ray photoelectron spectroscopy. *Applied Physics Letters*, **2006**, 89, 172101	3.4	21
112	Report on the 42nd IUVSTA workshop—Electron scattering in solids: from fundamental concepts to practical applications. *Surface and Interface Analysis*, **2006**, 38, 88-117	1.5	3
111	New universal expression for the electron stopping power for energies between 200 eV and 30 keV. *Surface and Interface Analysis*, **2006**, 38, 76-83	1.5	36
110	Dependence of calculated electron effective attenuation lengths on transport mean free paths obtained from two atomic potentials. *Surface and Interface Analysis*, **2006**, 38, 1348-1356	1.5	10

109	elsepaDirac partial-wave calculation of elastic scattering of electrons and positrons by atoms, positive ions and molecules. *Computer Physics Communications*, **2005**, 165, 157-190	4.2	410
108	Calculations of electron inelastic mean free paths. *Surface and Interface Analysis*, **2005**, 37, 1-14	1.5	160
107	Calculations of stopping powers of 100 eV to 30 keV electrons in 10 elemental solids. *Surface and Interface Analysis*, **2005**, 37, 978-988	1.5	54
106	Simulation of electron spectra for surface analysis (SESSA): a novel software tool for quantitative Auger-electron spectroscopy and X-ray photoelectron spectroscopy. *Surface and Interface Analysis*, **2005**, 37, 1059-1067	1.5	197
105	NIST databases with electron elastic-scattering cross sections, inelastic mean free paths, and effective attenuation lengths. *Surface and Interface Analysis*, **2005**, 37, 1068-1071	1.5	39
104	Summary of the panel discussion on opportunities and needs. *Surface and Interface Analysis*, **2005**, 37, 1072-1074	1.5	
103	Experimental determination of electron inelastic mean free paths in 13 elemental solids in the 50 to 5000 eV energy range by elastic-peak electron spectroscopy. *Surface and Interface Analysis*, **2005** , 37, 833-845	1.5	114
102	Monte Carlo strategies for simulations of electron backscattering from surfaces. *Surface and Interface Analysis*, **2005**, 37, 861-874	1.5	39
101	Origin of exchange decoupling effects in high-coercivity air-annealed CoPd multilayers. *Journal of Applied Physics*, **2005**, 97, 10J104	2.5	1
100	Interface intermixing and in-plane grain size in aluminum transition-metal bilayers. *Journal of Applied Physics*, **2004**, 96, 7278-7282	2.5	8
99	Artifacts in ballistic magnetoresistance measurements (invited). *Journal of Applied Physics*, **2004**, 95, 7554-7559	2.5	64
98	Summary of ISO/TC 201 Technical Report: ISO/TR 19319: 2003Surface chemical analysisAuger electron spectroscopy and x-ray photoelectron spectroscopyDetermination of lateral resolution, analysis area and sample area viewed by the analyser. *Surface and Interface Analysis*, **2004**, 36, 666-667	1.5	6
97	Effect of backscattered electrons on the analysis area in scanning Auger microscopy. *Applied Surface Science*, **2004**, 230, 327-333	6.7	18
96	Comparison of Electron Elastic-Scattering Cross Sections Calculated from Two Commonly Used Atomic Potentials. *Journal of Physical and Chemical Reference Data*, **2004**, 33, 409-451	4.3	184
95	Improvements in the Reliability of X-ray Photoelectron Spectroscopy for Surface Analysis. *Journal of Chemical Education*, **2004**, 81, 1734	2.4	6
94	Intermixing of aluminum-magnetic transition-metal bilayers. *Journal of Applied Physics*, **2003**, 93, 8044-8046	2.5	13
93	Thin Al, Au, Cu, Ni, Fe, and Ta films as oxidation barriers for Co in air. *Journal of Applied Physics*, **2003**, 93, 8731-8733	2.5	21
92	Calculation of electron inelastic mean free paths (IMFPs) VII. Reliability of the TPP-2M IMFP predictive equation. *Surface and Interface Analysis*, **2003**, 35, 268-275	1.5	326

91	Growth and trends in Auger-electron spectroscopy and x-ray photoelectron spectroscopy for surface analysis. *Journal of Vacuum Science and Technology A: Vacuum, Surfaces and Films*, **2003**, 21, S42-S53	2.9	27
90	Information depth and the mean escape depth in Auger electron spectroscopy and x-ray photoelectron spectroscopy. *Journal of Vacuum Science and Technology A: Vacuum, Surfaces and Films*, **2003**, 21, 274-283	2.9	72
89	Development of the web-based NIST X-ray Photoelectron Spectroscopy (XPS) Database. *Data Science Journal*, **2002**, 1, 1-12	2	24
88	Electron effective attenuation lengths for applications in Auger electron spectroscopy and x-ray photoelectron spectroscopy. *Surface and Interface Analysis*, **2002**, 33, 211-229	1.5	95
87	Measurement of silicon dioxide film thicknesses by X-ray photoelectron spectroscopy. *AIP Conference Proceedings*, **2001**,	0	2
86	Influence of elastic-electron scattering on measurements of silicon dioxide film thicknesses by x-ray photoelectron spectroscopy. *Journal of Vacuum Science and Technology A: Vacuum, Surfaces and Films*, **2001**, 19, 2604-2611	2.9	32
85	Comparisons of calculated and measured effective attenuation lengths for silicon dioxide over a wide electron energy range. *Surface Science*, **2001**, 488, L547-L552	1.8	27
84	Surface oxidation as a diffusion barrier for Al deposited on ferromagnetic metals. *Journal of Applied Physics*, **2001**, 89, 5209-5214	2.5	33
83	Evaluation of electron inelastic mean free paths for selected elements and compounds *Surface and Interface Analysis*, **2000**, 29, 108-114	1.5	57
82	Experimental determination of electron effective attenuation lengths in silicon dioxide thin films using synchrotron radiation I. Data analysis and comparisons. *Surface and Interface Analysis*, **2000**, 29, 330-335	1.5	13
81	Experimental determination of electron effective attenuation lengths in silicon dioxide thin films using synchrotron radiation II. Effects of elastic scattering. *Surface and Interface Analysis*, **2000**, 29, 336-340	1.5	9
80	Standard test data for estimating peak parameter errors in x-ray photoelectron spectroscopy: II. Peak intensities. *Surface and Interface Analysis*, **2000**, 29, 444-459	1.5	13
79	Standard test data for estimating peak parameter errors in x-ray photoelectron spectroscopy III. Errors with different curve-fitting approaches. *Surface and Interface Analysis*, **2000**, 29, 856-872	1.5	46
78	Hot-electron attenuation lengths in ultrathin magnetic films. *Journal of Applied Physics*, **2000**, 87, 5164-5166	2.5	20
77	Evaluation of electron inelastic mean free paths for selected elements and compounds **2000**, 29, 108		1
76	Consistency of calculated and measured electron inelastic mean free paths. *Journal of Vacuum Science and Technology A: Vacuum, Surfaces and Films*, **1999**, 17, 1122-1126	2.9	17
75	Relationships between electron inelastic mean free paths, effective attenuation lengths, and mean escape depths. *Journal of Electron Spectroscopy and Related Phenomena*, **1999**, 100, 137-160	1.7	128
74	Summary of ISO/TC 201 standards: introduction. *Surface and Interface Analysis*, **1999**, 27, 691-692	1.5	4

73	Evaluation of Calculated and Measured Electron Inelastic Mean Free Paths Near Solid Surfaces. *Journal of Physical and Chemical Reference Data*, **1999**, 28, 19-62	4.3	421
72	Energy calibration of X-ray photoelectron spectrometers. Part III: Location of the zero point on the binding-energy scale. *Surface and Interface Analysis*, **1998**, 26, 606-614	1.5	10
71	Standard test data for estimating peak parameter errors in x-ray photoelectron spectroscopy. I. Peak binding energies. *Surface and Interface Analysis*, **1998**, 26, 939-956	1.5	23
70	Evaluation of correction parameters for elastic-scattering effects in x-ray photoelectron spectroscopy and Auger electron spectroscopy. *Journal of Vacuum Science and Technology A: Vacuum, Surfaces and Films*, **1997**, 15, 2095-2106	2.9	43
69	Oxygen as a surfactant in the growth of giant magnetoresistance spin valves. *Journal of Applied Physics*, **1997**, 82, 6142-6151	2.5	183
68	Calculations of Electron Inelastic Mean Free Paths (IMFPs) VI. Analysis of the Gries Inelastic Scattering Model and Predictive IMFP Equation. *Surface and Interface Analysis*, **1997**, 25, 25-35	1.5	83
67	Development of standards for surface analysis by ISO technical committee 201 on surface chemical analysis. *Surface and Interface Analysis*, **1997**, 25, 860-868	1.5	9
66	Mean escape depth of signal photoelectrons from amorphous and polycrystalline solids. *Physical Review B*, **1996**, 54, 10927-10937	3.3	64
65	Low-temperature growth of giant magnetoresistance spin valves. *Journal of Applied Physics*, **1996**, 79, 282-290	2.5	15
64	Optimizing the giant magnetoresistance of symmetric and bottom spin valves (invited). *Journal of Applied Physics*, **1996**, 79, 5277	2.5	70
63	Growth of giant magnetoresistance spin valves using indium as a surfactant. *Journal of Applied Physics*, **1996**, 79, 2491-2496	2.5	71
62	Growth of giant magnetoresistance spin valves using Pb and Au as surfactants. *Journal of Applied Physics*, **1996**, 80, 5183-5191	2.5	58
61	The trade-off between large magnetoresistance and small coercivity in symmetric spin valves. *Journal of Applied Physics*, **1996**, 79, 8603-8606	2.5	13
60	Energy calibration of x-ray photoelectron spectrometers: Results of an interlaboratory comparison to evaluate a proposed calibration procedure. *Surface and Interface Analysis*, **1995**, 23, 121-132	1.5	53
59	Magnetoresistance values exceeding 21% in symmetric spin valves. *Journal of Applied Physics*, **1995**, 78, 273-277	2.5	116
58	Electron Inelastic Mean Free Paths in Organic Materials Especially for Polyethylene and Guanine.. *Hyomen Kagaku*, **1994**, 15, 175-180		
57	Calculations of electron inelastic mean free paths. V. Data for 14 organic compounds over the 50–2000 eV range. *Surface and Interface Analysis*, **1994**, 21, 165-176	1.5	1920
56	Activities of ISO technical committee 201 on surface chemical analysis. *Surface and Interface Analysis*, **1994**, 21, 615-620	1.5	7

55	Elastic-electron-scattering effects on angular distributions in x-ray-photoelectron spectroscopy. *Physical Review B*, **1994**, 50, 4739-4748	3.3	51
54	Calculations of electron inelastic mean free paths (IMFPS). IV. Evaluation of calculated IMFPs and of the predictive IMFP formula TPP-2 for electron energies between 50 and 2000 eV. *Surface and Interface Analysis*, **1993**, 20, 77-89	1.5	360
53	Formation of Technical Committee 201 on Surface Chemical Analysis by the International Organization for Standardization. *Surface and Interface Analysis*, **1993**, 20, 322-325	1.5	7
52	Formalism and parameters for quantitative surface analysis by Auger electron spectroscopy and x-ray photoelectron spectroscopy. *Surface and Interface Analysis*, **1993**, 20, 771-786	1.5	96
51	Formal databases for surface analysis: The current situation and future trends. *Surface and Interface Analysis*, **1991**, 17, 308-314	1.5	15
50	Calculations of electorn inelastic mean free paths. II. Data for 27 elements over the 50–2000 eV range. *Surface and Interface Analysis*, **1991**, 17, 911-926	1.5	1068
49	Calculations of electron inelastic mean free paths. III. Data for 15 inorganic compounds over the 50–2000 eV range. *Surface and Interface Analysis*, **1991**, 17, 927-939	1.5	575
48	Precision, accuracy, and uncertainty in quantitative surface analyses by Auger-electron spectroscopy and x-ray photoelectron spectroscopy. *Journal of Vacuum Science and Technology A: Vacuum, Surfaces and Films*, **1990**, 8, 735-763	2.9	205
47	Dependence of electron inelastic mean free paths on electron energy and materials at low energy region. I: Elements.. *Shinku/Journal of the Vacuum Society of Japan*, **1990**, 33, 58-62		2
46	Energy transfers in the quasielastic scattering of 70-1250-eV electrons by surfaces. *Physical Review B*, **1989**, 40, 7284-7287	3.3	8
45	The development of standards for surface analysis. *Surface and Interface Analysis*, **1988**, 11, 103-109	1.5	17
44	Calculations of electron inelastic mean free paths for 31 materials. *Surface and Interface Analysis*, **1988**, 11, 577-589	1.5	808
43	The status of reference data, reference materials and reference procedures in surface analysis. *Surface and Interface Analysis*, **1988**, 13, 46-50	1.5	11
42	New correlation effects observed for inner-shell excitations in titanium and vanadium. *Physical Review Letters*, **1987**, 58, 507-510	7.4	7
41	The energy dependence of electron inelastic mean free paths. *Surface and Interface Analysis*, **1987**, 10, 349-354	1.5	26
40	Surface chemical analysis—Report on the vamas project. *Surface and Interface Analysis*, **1986**, 9, 79-83	1.5	14
39	Characterization of the imaging properties of a double-pass cylindrical-mirror analyzer. *Surface and Interface Analysis*, **1986**, 9, 111-117	1.5	12
38	Imaging properties and energy aberrations of a double-pass cylindrical-mirror electron energy analyzer. *Journal of Vacuum Science and Technology A: Vacuum, Surfaces and Films*, **1986**, 4, 1551-1556	2.9	9

37	Recent developments in quantitative surface analysis by electron spectroscopy. *Journal of Vacuum Science and Technology A: Vacuum, Surfaces and Films*, **1986**, 4, 1532-1539	2.9	28
36	The energy dependence of electron attenuation lengths. *Surface and Interface Analysis*, **1985**, 7, 256-262	1.5	57
35	Calculations of electron inelastic mean free paths from experimental optical data. *Surface and Interface Analysis*, **1985**, 7, 263-274	1.5	45
34	Energy and material dependence of the inelastic mean free path of low-energy electrons in solids. *Journal of Vacuum Science and Technology A: Vacuum, Surfaces and Films*, **1985**, 3, 1338-1342	2.9	75
33	Innershell Ionization Cross Sections **1985**, 198-231		35
32	Summary Abstract: Comparison of L3-shell excitation energies of 3d transition metals obtained by XPS, AEAPS, and EELS. *Journal of Vacuum Science and Technology A: Vacuum, Surfaces and Films*, **1984**, 2, 840-841	2.9	4
31	X-ray photoemission spectroscopy of environmental particles. *Environmental Science & Technology*, **1984**, 18, 58-61	10.3	5
30	Variation of the threshold energies for core-electron excitation in electron energy-loss spectra as a function of incident electron energy. *Journal of Vacuum Science and Technology A: Vacuum, Surfaces and Films*, **1983**, 1, 1165-1168	2.9	10
29	Large Final-State Effects in the Core-Level Electron Energy-Loss Spectra of Vanadium at Low Incident-Electron Energies. *Physical Review Letters*, **1983**, 51, 61-64	7.4	21
28	Summary Abstract: Accurate determination of the energies of Auger electrons and photoelectrons from nickel, copper, and gold. *Journal of Vacuum Science and Technology*, **1982**, 20, 625-625		68
27	Progress of the ASTM E-42 committee on surface analysis. *Surface and Interface Analysis*, **1981**, 3, 94-98	1.5	11
26	L3VV Auger-Electron Line Shapes and Peak Positions for Near-Threshold Electron Excitation in Nickel and Copper. *Physical Review Letters*, **1981**, 46, 953-956	7.4	30
25	Surface analysis by electron spectroscopy at high pressures. *Journal of Vacuum Science and Technology*, **1978**, 15, 549-552		2
24	Determination of the Be Auger-electron attenuation length in Be using 160-keV protons. *Applied Physics Letters*, **1977**, 30, 357-359	3.4	13
23	Attenuation lengths of low-energy electrons in solids derived from the yield of proton-excited Auger electrons: beryllium and aluminum. *Physical Review B*, **1977**, 16, 1370-1379	3.3	43
22	Cross sections for ionization of inner-shell electrons by electrons. *Reviews of Modern Physics*, **1976**, 48, 33-47	40.5	325
21	Contrasting Valence-Band Auger-Electron Spectra for Silver and Aluminum. *Physical Review Letters*, **1973**, 30, 1179-1182	7.4	153
20	Semiautomated Data-Recording and Control System for an Electron Energy Analyzer. *Review of Scientific Instruments*, **1973**, 44, 1031-1033	1.7	2

19	High-Resolution Measurements of the L3M2,3 M4,5 Auger Transitions in Nickel and Copper. *Physical Review Letters*, **1972**, 29, 1153-1156	7.4	30
18	High-Resolution Measurements of Auger-Electron and Photoelectron Structure in the Secondary-Electron Energy Distributions of Aluminum, Nickel, and Copper. *Physical Review B*, **1972**, 6, 4418-4429	3.3	21
17	Structure on the High-Energy Side of the KL23M Auger Peak from Solid Aluminum: Internal Photoemission. *Applied Physics Letters*, **1972**, 20, 335-337	3.4	11
16	Validity of Inelastic-Electron-Scattering Data in Determining the Metallic or Insulating Properties of Adsorbed Atomic Layers. *Physical Review B*, **1970**, 1, 4191-4192	3.3	6
15	Excitation of L-Shell Electrons in Al and Al2O3 by 20-keV Electrons. *Physical Review*, **1968**, 167, 592-600		32
14	Characteristic Energy Losses of 8-keV Electrons in Liquid Al, Bi, In, Ga, Hg, and Au. *Physical Review*, **1968**, 175, 972-982		135
13	Inelastic scattering of kilovolt electrons by solids and liquids: determination of energy losses, cross sections, and correlations with optical data. *Health Physics*, **1967**, 13, 1265-75	2.3	18
12	Inelastic Scattering Cross Sections for 20-keV Electrons in Al, Be, and Polystyrene. *Physical Review*, **1966**, 145, 195-208		56
11	Plasmon Damping in Metals. *Physical Review*, **1966**, 145, 209-217		47
10	Differences in the Characteristic Electron Energy-Loss Spectra of Solid and Liquid Bismuth. *Physical Review Letters*, **1965**, 15, 852-854	7.4	20
9	Excitation of Electrons in Polystyrene and Similar Polymers by 20-keV Electrons. *Journal of Chemical Physics*, **1963**, 39, 630-634	3.9	41
8	Effect of Oxidation on the Characteristic Loss Spectra of Aluminum and Magnesium. *Physical Review*, **1960**, 118, 640-643		182
7	Origin of the Characteristic Electron Energy Losses in Aluminum. *Physical Review*, **1959**, 115, 869-875		313
6	Origin of the Characteristic Electron Energy Losses in Magnesium. *Physical Review*, **1959**, 116, 81-83		86
5	Effects of Contamination on the Characteristic Loss Spectrum of Tungsten. *Physical Review*, **1958**, 110, 657-660		43
4	Calculations of electron inelastic mean free paths. XIII. Data for 14 organic compounds and water over the 50 eV to 200 keV range with the relativistic full Penn algorithm.. *Surface and Interface Analysis*,	1.5	2
3	The coordinated development of standards for surface chemical analysis		3
2	Simulation of electron spectra for surface analysis (SESSA) version 2.1 user's guide		4

1	Martin Seah: An extraordinary scientist and metrologist. *Surface and Interface Analysis*,	1.5	2